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PUMA 84S32000 - 70/85/10

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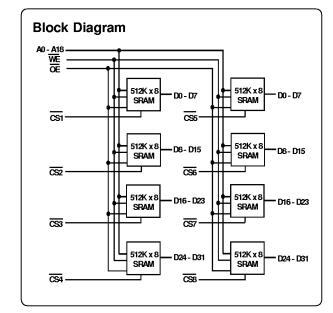
Description

The PUMA 84S32000 is a 32Mbit CMOS Static RAM organised as 1M x 32 in a JEDEC 84 pin surface mount J-leaded PLCC, available with access times of 70, 85, and 100ns. The output width is user configurable as 8, 16 or 32 bits using eight Chip Selects (CS1~8).

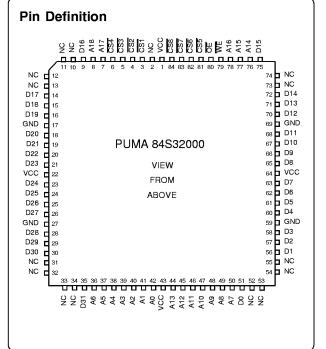
The PUMA 84S32000 offers a dramatic space saving advantage over eight standard 512Kx8 devices. The -L version has data retention capability and can be used in battery backup applications.

Features

- Access times of 70/85/100 ns.
- · High Density Package
- JEDEC 84 'J' leaded plastic Surface Mount Package.
- Single 5.0 V±10% Power supply.
- User Configurable as 8 / 16 / 32 bit wide output.
- Operating Power (32-BIT) 2.51 W (max)
 Low Power Standby (-L) 8.25 mW (max)
- · Fully Static operation.
- · Data Retention Capability (-L version only).
- Multiple ground pins for maximum noise immunity.



Pin Functions Address Inputs A0 ~ A18 D0 ~ D31 Data Input/Output Chip Select CS1 ~ 8 WE Write Enable Output Enable <u>OE</u> No Connect NC Power (+5V) V_{cc} **GND** Ground



Package Details

Plastic 84 J-Leaded JEDEC PLCC

DC OPERATING CONDITIONS

Absolute Maximum Ratings (1)			
Voltage on any pin relative to GND	V	-0.3V to 7.0	V
Power Dissipation	ν _⊤ Ρ ₋	4.5	W
Storage Temperature	T _{STG}	-55 to +125	°C

Notes (1) Stresses above those listed may cause permanent damage. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Recommended Operating Conditions										
Parameter	Symbol	min	typ	max	Units	:				
Supply Voltage	V _{cc}	4.5	5.0	5.5	٧					
Input High Voltage	V _{IH}	2.2	-	$V_{CC} + 0.3$	V					
Input Low Voltage	V _{II} (1)	-0.3	-	8.0	V					
Operating Temperature	T _A	0	-	70	.C					
	TAI	-40	-	85	.C	(Suffix I)				

Notes: (1) Pulse width: -3.0V for less than 40ns.

DC Electrical Characteris	tics (V _c	ے5V±	10%,T _A =-40°C to +85°C)				
Parameter	٤	Symbol	Test Condition	min	typ	max	Unit
Input Leakage Current Output Leakage Current		 _{LI1} _{LO}	V_{IN} =0V to V_{CC} $V_{I/O}$ =0V to V_{CC}	-8 -8	-	8 8	μ Α μ Α
Operating Supply Current ⁽²⁾	32 bit 16 bit 8 bit	I _{CC32} I _{CC16} I _{CC8}	Cycle time = min 100% duty $I_{I/O}$ =0mA CS= V_{IL} V_{IN} = V_{IH} or V_{IL} As above. As above.	- - -	- - -	456 244 138	mA mA mA
Standby Supply Current -L Version ((TTL) (CMOS)	 _{SB} _{SB1}	$\frac{\overline{CS}^{(1)}=V_{IH}, V_{IN}=V_{IL} \text{ or } V_{IH}}{\overline{CS} \ge V_{CC}^{-}0.2V, \text{ Other inputs} = 0 \sim V_{CC}^{-}$	-	-	32 2	mA mA
Output Voltage Low Output Voltage High	$oldsymbol{V}_OH$		2.1mA,V _{CC} =Min 1.0mA,V _{CC} =Min	- 2.2	-	0.4 -	V V

Notes: (1) $\overline{CS1} \sim 4$ or $\overline{CS5} \sim 8$ inputs operate simultaneously for 32 bit mode.

Capacitance (V _{cc} =5V, T _A =25°C, F=1Mh:	z)					
Parameter	Symbol	Test Condition	min	typ	max	Unit
Input Capacitance Address, OE, WE	C _{IN1}	$V_{IN} = 0V$	-	-	64	pF
Output Capacitance 8-bit mode (worst case)	$C_{I/O}$	$V_{VO} = 0V$	-	-	80	pF

Note: These parameters are calculated, not measured.

AC Test Conditions

Output Load

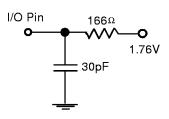
*Input pulse levels: 0.8V to 2.4V

*Input rise and fall times: 5 ns

*Input and Output timing reference levels: 1.5V

*V_{cc}=5V±10%

*PUMA module is tested in 32 bit mode.



Operation Truth Table

Below is the truth table which applies to each individual SRAM on the module. When operating the module care should be taken to prevent any two SRAM components which are connected to the same data byte from driving the bus simultaneously. This will prevent bus contention occurring on the module. Please refer to the block diagram on the front page of this datasheet.

Mode	cs	ŌĒ	WE	V _{cc} Current	I/O Pin	Reference Cycle
Not Selected	1	Х	Х	_{SB1} , _{SB2}	High Z	Power Down
Output Disable	0	1	1	I _{CC1}	High Z	
Read	0	0	1	I _{CC1}	D _{OUT}	Read Cycle
Write	0	Х	0	I _{CC1}	D _{IN}	Write Cycle

$$1 = V_{_{IH}}, \hspace{1cm} 0 = V_{_{IL}}, \hspace{1cm} X = Don't Care$$

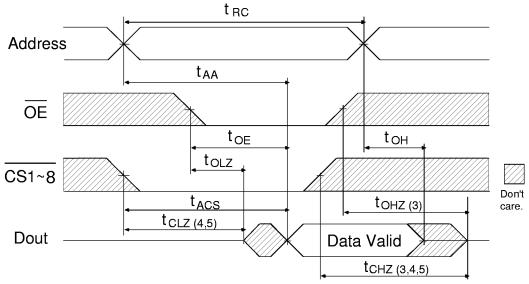
Low V _{cc} Data Retention C	haracterist	ics - L version only				
Parameter	Symbol	Test Condition	min	typ	max	Unit
V _{cc} for Data Retention	$V_{_{\mathrm{DB}}}$	CS=V _{cc} -0.2V	2.0	-	-	٧
Data Retention Current	(1)	$V_{CC} = 3.0VA, CS > V_{CC}-0.2V, V_{IN} > 0V$	-	-	1.5	mA
Data Retention Time	$t_{_{\mathrm{CDR}}}$	See Retention Waveform	0	-	-	ns
Operation Recovery Time	t _p	See Retention Waveform	5	-	-	ms

AC OPERATING CONDITIONS

Read Cycle		7	70	g	?5	-	10	
Parameter	Symbol	min ,	max	min	max	min	max	Units
Read Cycle Time	t _{RC}	70	-	85	-	100	-	ns
Address Access Time	t _{AA}	-	70	-	85	-	100	ns
Chip Select Access Time	t _{ACS}	-	70	-	85	-	100	ns
Output Enable to Output Valid	t _{oe}	-	35	-	45	-	50	ns
Output Hold from Address Change	t_{\scriptscriptstyleOH}	10	-	10	-	15	-	ns
Output Enable to Output in Low Z	$t_{\scriptscriptstyleOLZ}$	5	-	5	-	5	-	ns
Output Disable to Output in High Z	t_{OHZ}	0	25	0	25	0	30	ns
Chip Disable to Output in High Z	$t_{\scriptscriptstyleCHZ}$	0	25	0	25	0	30	ns
Chip Enable to Output in Low Z	$t_{\scriptscriptstyle{CLZ}}$	10	0	10	0	10	0	ns

Write Cycle								
		7	70	8	 35	1	0	
Parameter	Symbol	min	max	min	max	min	max	Units
Write Cycle Time	t_{wc}	70	-	85	-	100	-	ns
Chip Selection to End of Write	t_{cw}	60	-	70	-	80	-	ns
Address Valid to End of Write	t_{AW}	60	-	70	-	80	-	ns
Address Setup Time	t _{as}	0	-	0	-	0	-	ns
Write Pulse Width	t_{WP}	50	-	60	-	70	-	ns
Write Recovery Time	t_{w_R}	0	-	0	-	0	-	ns
Data to Write Time Overlap	t_{\scriptscriptstyleDW}	30	-	35	-	40	-	ns
Output Active from End of Write	t_{ow}	3	-	3	-	3	-	ns
Data Hold from Write Time	t_{\scriptscriptstyleDH}	0	-	0	-	0	-	ns
Write to Output High Z	t_{wHz}	0	25	0	25	0	30	ns

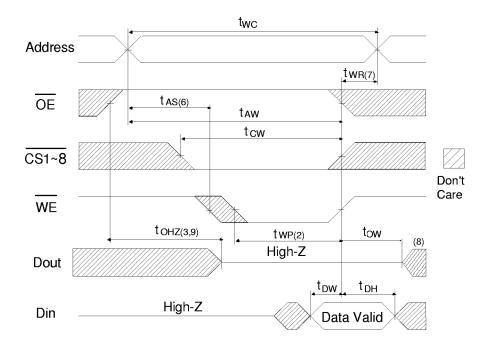
Read Cycle Timing Waveform (1.2)



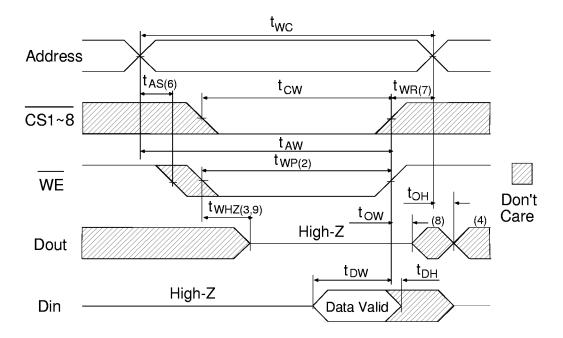
AC Read Characteristics Notes

- (1) WE is High for Read Cycle.
- (2) All read cycle timing is referenced from the last valid address to the first transition address.
- (3) t_{CHZ} and t_{OHZ} are defined as the time at which the outputs achieve open circuit conditions and are not referenced to output voltage levels.
- (4) At any given temperature and voltage condition, t_{CHZ} (max) is less than t_{CLZ} (min) both for a given module and from module to module.
- (5) These parameters are sampled and not 100% tested.

Write Cycle No.1 Timing Waveform(1.4)



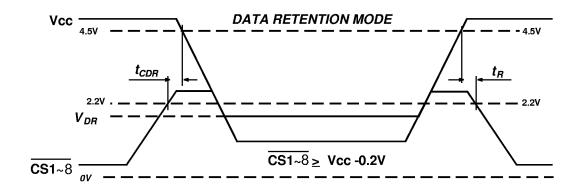
Write Cycle No.2 Timing Waveform (1,5)



AC Write Characteristics Notes

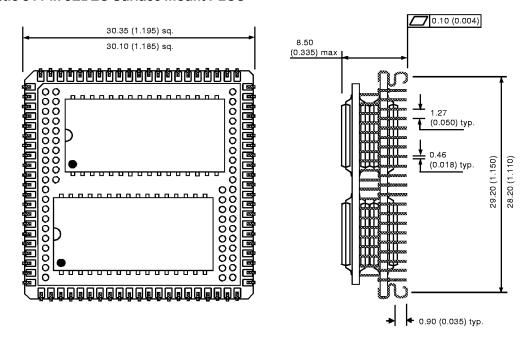
- (1) All write cycle timing is referenced from the last valid address to the first transition address.
- (2) All writes occur during the overlap of $\overline{CS1} \sim 8$ and \overline{WE} low.
- (3) If \overline{OE} , $\overline{CS1} \sim 8$, and \overline{WE} are in the Read mode during this period, the I/O pins are low impedance state. Inputs of opposite phase to the output must not be applied because bus contention can occur.
- (4) Dout is the Read data of the new address.
- (5) \overline{OE} is continuously low.
- (6) Address is valid prior to or coincident with $\overline{CS1} \sim 8$ and \overline{WE} low, too avoid inadvertant writes.
- (7) CS1~8 or WE must be high during address transitions.
- (8) When CS is low: I/O pins are in the output state. Input signals of opposite phase leading to the output should not be applied.
- (9) Defined as the time at which the outputs achieve open circuit conditions and are not referenced to output voltage levels. These parameters are sampled and not 100% tested.

Data Retention Waveform

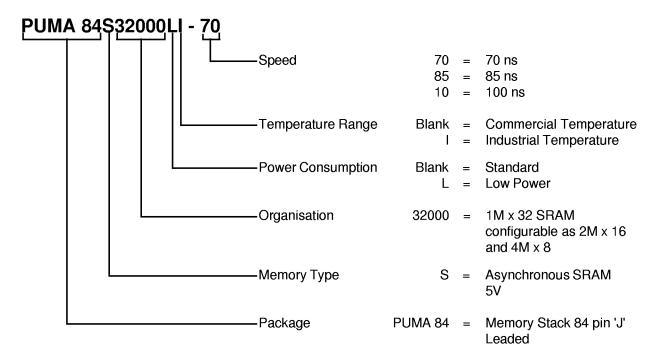


Package Information Dimensions in mm(inches)

Plastic 84 Pin JEDEC Surface mount PLCC



Ordering Information



Note:

Although this data is believed to be accurate, the information contained herein, is not intended to and does not create any warranty of merchantibility or fitness for a particular purpose.

Our products are subject to a constant process of development. Data may be changed at any time without notice. Products are not authorised for use as critical components in life support devices without the express approval of a company director.